

Optimization of Redundancy by using Genetic Algorithm for Reliability of Plant Protection System

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(Redundancy)

(Local minimum)

(MIL-HDBK-217)

ABSTRACT

The design and development of a reliable protection system has been becoming a key issue in industry field because the reliability of system is considered as a important factor to perform the system's function successfully. Plant Protection System(PPS) guarantees the safety of plant by accident detection and control action against the transient conditions of plant.

This paper presents the analysis of PPS reliability and the formal problem statement about optimal redundancy based on the reliability of PPS. And the optimization problem is solved by genetic algorithm. The genetic algorithm is a useful tool to solve the problems, in the case of large searching, complex gradient, existence local minimum. The effectiveness of the proposed optimization technique is proved by the target reliability of one channel of PPS, using the failure rate based on the MIL-HDBK-217.

I.

가 FA 가
(FA)

[1-5]

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가

(Redundancy)

(Local minimum)

[6-7]

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(MIL - HDBK - 217)

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1

(Input 1=Input 2=Input 3=Input 4)

(Redundancy)

(Voter) 4 2

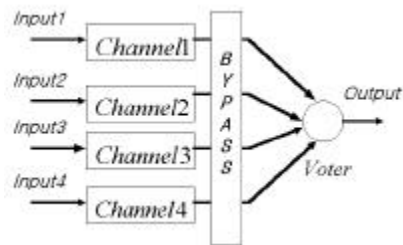
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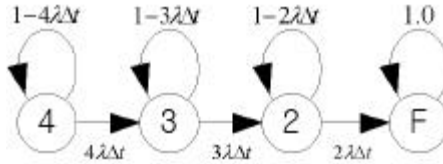
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2.1

(Markov model)

λ 가



2

$$P(t) \quad t$$

(1) (3)

$$\frac{dP_4(t)}{dt} = -4\lambda P_4(t) \tag{1}$$

$$\frac{dP_3(t)}{dt} = 4\lambda P_4(t) - 3\lambda P_3(t) \tag{2}$$

$$\frac{dP_2(t)}{dt} = 3\lambda P_3(t) - 2\lambda P_2(t) \tag{3}$$

$$\frac{dP_F(t)}{dt} = 2\lambda P_2(t) \tag{4}$$

(t=0)

$$P_4(0) = 1, \quad P_3(0) = P_2(0) = P_F(0) = 0$$

(1-3) (5-7)

$$P_4 = e^{-4\lambda t} \tag{5}$$

$$P_3 = 4e^{-3\lambda t} - 4e^{-4\lambda t} \tag{6}$$

$$P_2 = 6e^{-2\lambda t} - 12e^{-3\lambda t} + 6e^{-4\lambda t} \tag{7}$$

1

$P_4 \quad P_3$

$$P_2 \tag{8}$$

$$R_{pps} = P_4 + P_3 + P_2 \tag{8}$$

$$= 6e^{-2\lambda t} - 8e^{-3\lambda t} + 3e^{-4\lambda t}$$

MTTF (9)

$$MTTF_{pps} = \int_0^{\infty} R_{pps}(t) dt \tag{9}$$

$$= \frac{13}{12\lambda}$$

가 (steady-state availability: $A(\infty) = A_{ss}$)

$$A_{ss-pps} = \frac{MTTF}{MTTF + MTTR} \tag{10}$$

$$MTTR = \frac{1}{\mu}, \quad \mu \text{ (repair rate)}$$

3

. A

(λ)

$$1 * 10^{-4}$$

, B

$$2 * 10^{-4}$$

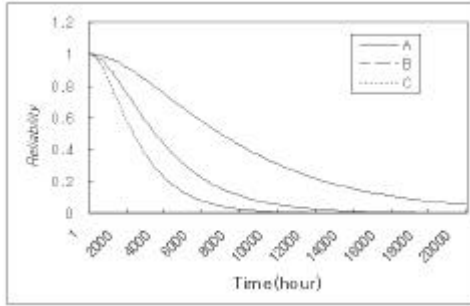
$$C \quad 3 * 10^{-4}$$

4

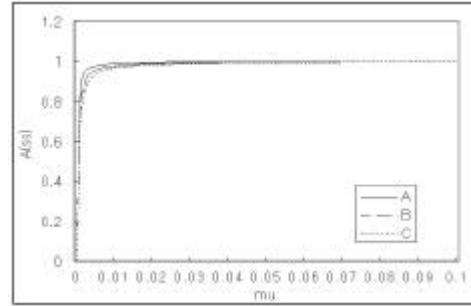
μ

(maintenance rate)

가



6 PPS



7 Bypassed PPS MTR

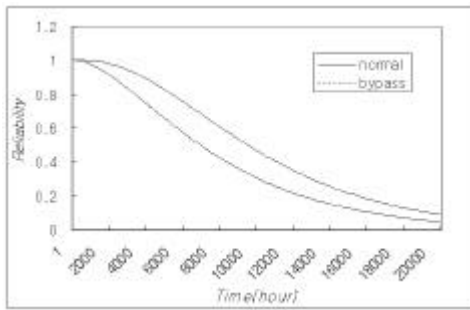
(A: $1 * 10^{-4}$, B: $2 * 10^{-4}$, C: $3 * 10^{-4}$)

8

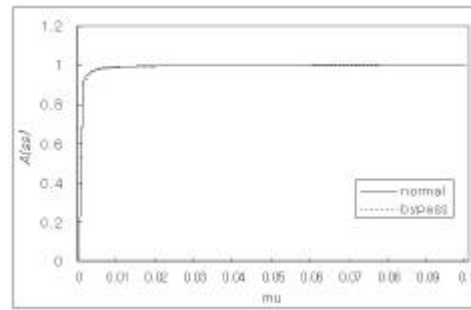
9

가

$1 * 10^{-4}$



8 normal case PPS bypass case PPS



9 normal case PPS bypass case PPS 가

가

가

1

가

(Redundancy)

(Redundancy) 가

m2

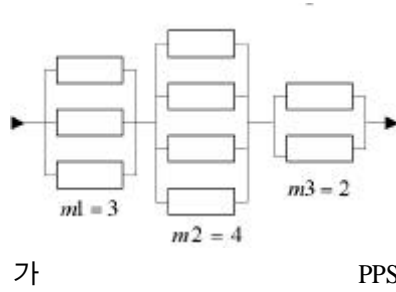
PPS

m1

, m3

10

가
(redundancy)



(16) 가 (weight value) , m_i 가 , w_i 가 , N

$$\text{Minimize } \left\{ \sum_{i=1}^N w_i m_i \right\} \quad (16)$$

$$\text{subject to } \prod_{i=1}^N R_i(t) \geq R^*$$

$$\text{and } 0 \leq R_i \leq 1 \quad \forall_i$$

$$R^* = R_i \quad i, 1/k$$

$$(16) \quad \text{가} \quad (17)$$

$$(\phi) \quad \gamma$$

$$\text{Minimize } \left\{ \sum_{i=1}^N w_i m_i + \gamma \phi \left(\prod_{i=1}^N R_i(t) \right) \right\} \quad (17)$$

$$\phi = [\min(\prod_{i=1}^N R_i(t) - R^*, 0)]^2 \quad (18)$$

$$(19)$$

$$(20)$$

$$\text{Maximize } \left\{ \frac{1}{\sum_{i=1}^N w_i m_i + \gamma \phi \left(\prod_{i=1}^N R_i(t) \right)} \right\} \quad (19)$$

$$\text{Fitness} = \frac{1}{\sum_{i=1}^N w_i m_i + \gamma \phi \left(\prod_{i=1}^N R_i(t) \right)} \quad (20)$$

1

가 가

가

(natural selection)

(generation)

(Local minimum)

1. (one-chromosome individual)

2. (population)

3.

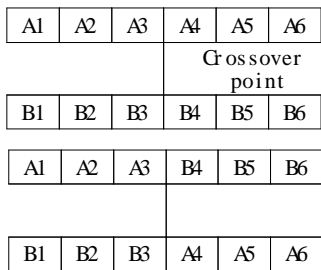
1) (Coding) : 2

2) 가(Evaluation) : (fitness) 가

3) (Reproduction) : (

roulette wheel selection)

4) (Crossover) : 가



5) (Mutation) :

C1	C2	C3	C4	C5	C6
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C1	C2	F3	C4	C5	C6
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가

1

가

MIL-HDBK-217

10^6

1 A/D

1

2 2 DSP(320C50) , PLD

3 1 3

가 :

1. (Connection)

2. (Voter)

1 Box 1

Part Number		(10^6 hour)		(10^6 hour)
1674	12bit A/D Converter	0.080981	10	0.80981
7770- 12	Dual power supervisor	1.101960	1	1.101960
2860	Power supply controller	0.077565	1	0.077565
2544	Power supply circuit	0.057856	1	0.057856
1 Box1				: 2.047193

2 Box 2

Part Number		(10^6 hour)		(10^6 hour)
320C50	DSP processor	0.609501	4	2.438004
27PC256	PROM	0.121793	16	1.948688
62990	Fast SRAM	0.159277	16	2.548432
7064	PLD	0.173746	4	0.694984
7770- 12	Dual power supervisor	1.101960	2	2.20392
2860	Power supply controller	0.077565	2	0.15513
2544	Power supply circuit	0.057856	2	0.11573
1 Box2				: 10.104888

3 Box 3

Part Number		(10^6 hour)		(10^6 hour)
320C50	DSP processor	0.609501	2	1.219002
27PC256	PROM	0.121793	8	0.974344
62990	Fast SRAM	0.159277	8	1.274216
7064	PLD	0.173746	2	0.347492
7770- 12	Dual power supervisor	1.101960	1	1.101960
2860	Power supply controller	0.077565	1	0.077565
2544	Power supply circuit	0.057856	1	0.057856
1 Box3				: 5.052435

1-3

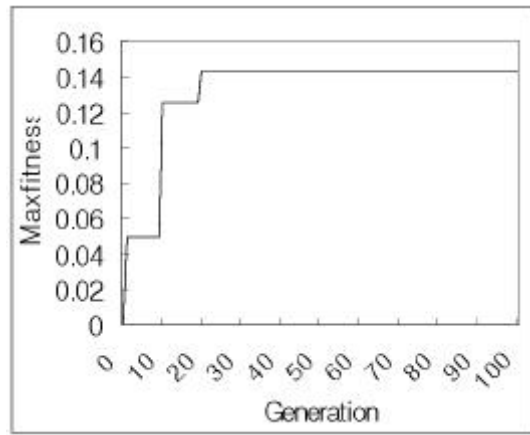
가 . 2가 가

가 . 가 가 w_i 가
 가 가 가 가 $w_1 = 1, w_2 = 1, w_3 = 1$ 가
 가 가 $w_4 = 5 * 10^3$. 4

4

Population size	: 100
Probability of crossover P_c :	0.7
Probability of mutation P_m	: 0.1
Number of generation	: 10

20000(Hour) 0.95 .
 0.1429 , box 1 1 , box 2 3 , box 3 3 .
 (R_{ch-1}) 0.9532 . R1=0.9599,
 R2=0.9939, R3= 0.9991 . 11
 가 .



11

Maxfitness

(Redundancy)
(MIL-HDBK-217)

1

safety , voter

(Segmentation)

Acknowledgement

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